Applicant(s)/Patent Under Reexamination 10/042,359 ONG ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Duc Truong 1711

Application/Control No.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	Α	US-				
	В	US-				
	C	US-				
	D	US-				
	Ε	US-				
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	G	US-				
	Н	US-				
	1	US-				
	J	US-				
	К	US-			1.	
	L	US-				
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

	HOIST ATENT BOOKINGTO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	J	Bellette et al, "Spectroscopy and photophysics of some oligomers and polymers derived from thiophenes", 1995, Chem Abstract 123: 315123						
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	w							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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